

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002-01 Issue No.: 5 Status: Current

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Integrated Service Technology, Inc.

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The organization, facilities and procedures have been assessed and found to comply with the applicable requirements for Independent Testing Laboratory organization approval, in support of the IECQ system, which is in accordance with the Basic Rules IECQ 01 and Rules of Procedure IECQ 03-6 "Independent Testing Laboratory Assessment Program Requirements" of the IEC Quality Assessment System for Electronic Components (IECQ) and applicable requirements of ISO/IEC 17025:2017 for the testing of electronic components under the IECQ.

Scope:

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

See attached Schedule of Scope

- Attached Schedule: IECQ-L DEKRA 16.0002-01-S Rev3.pdf

Issued by the Certification Body: DEKRA Certification B.V.

Meander 1051 Arnhem Netherlands

Authorised Person: Ted Gaertner



Site Added: 2016/08/17



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

This Certificate of Conformity may be suspended or withdrawn in accordance with the

Rules of Procedure of the IECQ System and its Schemes.

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002-01
CB Certificate No.: DEKRA-T5B-003

Schedule Number: IECQ-L DEKRA 16.0002-01-S Rev No.: 3 Rev. Date: 2019/08/19 Page 1 of 1

1. Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military accelerated environment reliability stress tests (Including: Pre-condition / MSL / Accelerated Temperature-Humidity test / Temperature-Humidity with bias test / Temperature Cycling test / Power and temperature cycling / Temperature storage test / IOL / Salt)	J-STD-020, JESD22-A101/A102/A106/A107/A110/A113/ A118/A119; IEC-60068-2-1/2/3/14/ 38/52, MIL-STD-202/750/810/883, JESD JP001; EIA-364-32C, EIAJ ED-4701, AEC-Q200-001 /004; AEC-Q005/Q006,	Or customer specified test
Consumer/ Commercial / Industrial (JESD 47) and Automotive / Military accelerated lifetime simulation tests. (Including: Temperature, Bias, and Operating Life test / early life failure rate / Endurance and Data retention test / Electro-Migration / Short circuit / Miscellaneous test / Gate Leakage test)	JESD22-A108/A117, JESD61, MIL-STD-202/750/810/883, AEC-Q100-005/006/008/012, AEC-Q101-004/006, Customer standards	Or customer specified test
Failure and material analysis of semiconductor IC (TEM / SEM / DUAL BEAM FIB), electronic components and PCB/PCBA, including FIB (Focused Ion Beam), Electrical Analysis, Sample Preparation (Decap, X-section, etc), NDE (Nondestructive Engineering), Physical & Chemical Analysis (Including Hazardous Substances) and IC package.	IPC-TM-650, IPC-610, J-STD-020, JEDEC-C201, EIA-469, IEC62321, EN14582,	Or customer specified test
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military electromagnetic compatibility and electrostatic discharge test. (Including: HBM / MM / CDM / Latch Up / ESD Gun)	IEC 61967/1-3, JESD22-A114/A115/C101, EIA/JESD78, ANSI JEDEC ESDA JS001/JS002; ISO-10605, AEC-Q100-002/003/004/011, AEC-Q101-001/002/005, AEC-Q200-002, JEITA ED4701; IEC61000-4-2, MIL-STD-202/750/810/883	Or customer specified test

This schedule is only valid in conjunction with the referenced Certificate of Approval
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